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 Inputs Are TTL-Voltage Compatible 3-State Outputs Interface Directly With 	DB, DW, OR N PACKAGE (TOP VIEW)
System Bus	
 Flow-Through Architecture Optimizes PCB Layout 	A/B 1 20 1A 1Y 2 19 1B 2Y 3 18 2A
 Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise 	GND [4 17] 2B GND [5 16] V _{CC}
 EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process 	GND [] 6 15 [] V _{CC} GND [] 7 14 [] 3A
 500-mA Typical Latch-Up Immunity at 125°C 	3Y [8 13] 3B 4Y [9 12] 4A
 Provides Bus Interface From Multiple Sources in High-Performance Systems 	OE [10 11] 4B
Package Options Include Plastic	

Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages, and Standard Plastic 300-mil DIPs (N)

description

The 74ACT11257 is designed to multiplex signals from 4-bit data sources to four output data lines in bus-organized systems. The 3-state outputs do not load the data lines when the output-enable (\overline{OE}) input is at a high logic level.

The 74ACT11257 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE								
	INPUT							
	SELECT	DA	TA	OUTPUT				
OE	Ā/B	Α	В	•				
н	Х	Х	Х	Z				
L	L	L	Х	L				
L	L	н	Х	Н				
L	н	Х	L	L				
L	Н	Х	Н	Н				

FUNCTION TABLE



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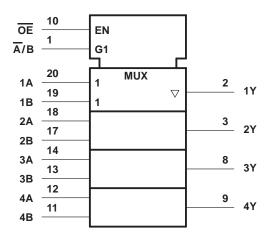
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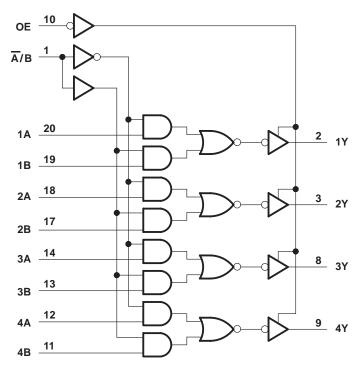
74ACT11257 **QUADRUPLE 2-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER** WITH 3-STATE OUTPUTS SCAS053B - JANUARY 1989 - REVISED APRIL 1996

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

N package	$\begin{array}{c} -0.5 \ \text{V to } \ \text{V}_{CC} + 0.5 \ \text{V} \\ -0.5 \ \text{V to } \ \text{V}_{CC} + 0.5 \ \text{V} \\ \pm 20 \ \text{mA} \\ \pm 50 \ \text{mA} \\ \pm 50 \ \text{mA} \\ \pm 100 \ \text{mA} \\ \dots & 1.6 \ \text{W} \\ \dots & 1.3 \ \text{W} \end{array}$
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

recommended operating conditions

		MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	V
VIH	High-level input voltage	2		V
VIL	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
VO	Output voltage	0	VCC	V
ЮН	High-level output current		-24	mA
IOL	Low-level output current		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
ТА	Operating free-air temperature	-40	85	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETEDS	TEST CONDITIONS	N	T _A = 25°C				MAY	UNIT
PARAMETERS		VCC	MIN	TYP	MAX	MIN	MAX	UNIT
		4.5 V	4.4			4.4		
	I _{OH} = -50 μA	5.5 V	5.4			5.4		
VOH		4.5 V	3.94			3.8		V
	$I_{OH} = -24 \text{ mA}$	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
					0.1		0.1	
	I _{OL} = 50 μA	5.5 V			0.1		0.1	V
VOL		4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
I _{OZ}	$V_{O} = V_{CC} \text{ or } GND$	5.5 V			±0.5		±5	μΑ
l	$V_{I} = V_{CC} \text{ or } GND$	5.5 V			±0.1		±1	μΑ
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			8		80	μA
ΔI_{CC}^{\ddagger}	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1	mA
Ci	$V_{I} = V_{CC}$ or GND	5 V		3.5				pF
Co	$V_{O} = V_{CC}$ or GND	5 V		8				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to V_{CC}.

switching characteristics over recomended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

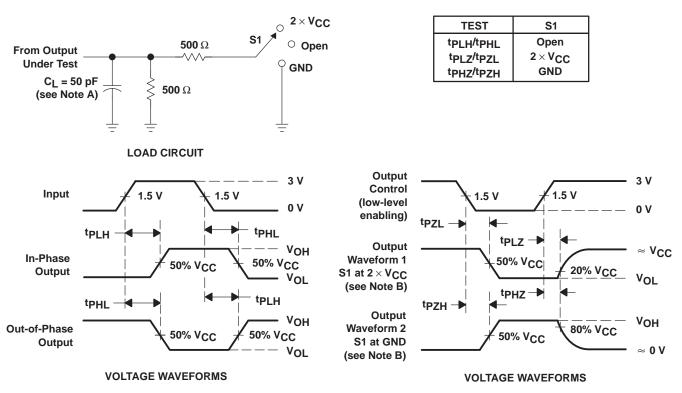
	FROM	ТО	т	Δ = 25°C	:			
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	UNIT
^t PLH	A or P	Y -	1.5	4.4	6.4	1.5	6.9	ns
^t PHL	A or B		1.5	5	8	1.5	8.7	
^t PLH	Ā/B	Anu X	1.5	4.7	7.6	1.5	8.2	
^t PHL		Any Y	1.5	5.7	8.5	1.5	9.4	ns
^t PZH		Amy V	1.5	4.2	6.9	1.5	7.3	
^t PZL	ŌE	Any Y	1.5	5.5	8.7	1.5	9.6	ns
^t PHZ	ŌĒ	Δου Χ	1.5	5.7	7.6	1.5	8.4	
^t PLZ		Any Y	1.5	6	7.9	1.5	8.5	ns

operating characteristics, V_{CC} = 5 V, T_A = 25° C

PARAMETER			TEST CON	TYP	UNIT	
C _{pd}	Dower dissipation conscitance	Outputs enabled	C _L = 50 pF,	f = 1 MHz	41	pF
	Power dissipation capacitance	Outputs disabled			13	



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_Q = 50 Ω , t_f = 3 ns, t_f = 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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